

Figure 3 Electronics layout showing CEM Bias, and data processing electronics

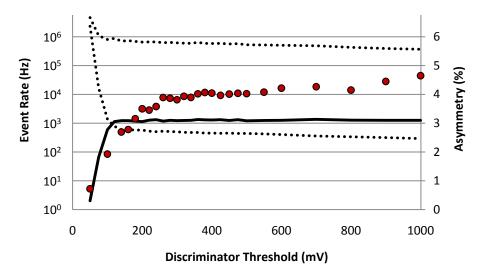


Figure 4: Count rate with incident beam on (upper dotted line) and off (lower dotted line). Asymmetry (circles) vs. CEM discriminator thresholds (see text). Solid line is the signal-to-noise ratio. Data shown is for 5 kV with superlattice photocathode and 773 nm laser illumination.